

Integrated Device Technology, Inc. 6024 Silver Creek Valley Road, San Jose, CA - 95138

PRODUCT/	PROCESS CH	IANGE NOTI	CE (PCN)
PCN #: TB1904-01  Product Affected: P9242-G2NDGI P9242-G2NDGI8	DATE: <b>29-Apr-2019</b>	MEANS OF DISTING  □ Product Mark  □ Back Mark  □ Date Code  ■ Other	GUISHING CHANGED DEVICES:  Traceability to the test location is maintained by IDT and available on request
Date Effective: 29-Jul-2019			
Contact: IDT PCN DESK		Attachment:	Yes No
E-mail: <pre>pcndesk@idt.com</pre>		Samples: Please contains sample requirements	act your local sales representative for lest.
DESCRIPTION AND PURPOSE OF CHA	ANGE:		
<ul> <li>□ Die Technology</li> <li>□ Wafer Fabrication Process</li> <li>□ Assembly Process</li> <li>□ Equipment</li> <li>□ Material</li> <li>□ Testing</li> <li>■ Manufacturing Site</li> <li>□ Data Sheet</li> <li>□ Other</li> </ul>		facilities for Test proce Penang, Malaysia facili	t IDT is adding KYEC and ASEK, as for the selective products that are ty.
RELIABILITY/QUALIFICATION SUM  There is no expected change to the product correlation data.		formance. Please refer	to Attachment I for Electrical
CUSTOMER ACKNOWLEDGMENT O  IDT records indicate that you require writte to grant approval or request additional infor it will be assumed that this change is accept IDT reserves the right to ship either version on the earlier version has been depleted.	n notification of this cha mation. If IDT does not able.	receive acknowledgem	ent within 30 days of this notice
Customer:		Approval for sh	ipments prior to effective date.
Name/Date:	E-	Mail Address:	
Title:	Ph	none# /Fax# :	
CUSTOMER COMMENTS:			
IDT ACKNOWLEDGMENT OF RECEI	PT:	DATE.	
RECD. BY:		DATE:	



Integrated Device Technology, Inc. 6024 Silver Creek Valley Road, San Jose, CA - 95138

### PRODUCT/PROCESS CHANGE NOTICE (PCN)

#### ATTACHMENT I - PCN # : TB1904-01

**PCN Type:** Manufacturing Site - Alternate Test Locations

**Data Sheet Change:** None

**Detail Of Change:** 

This notification is to advise our customers that IDT is adding KYEC and ASEK, Taiwan as alternate facilities for Test process for the selective products that are presently tested in IDT Penang, Malaysia facility.

This change will allow IDT the flexibility to ship from either facilities and will provide the increased capacity, flexibility and shorter lead time to meet market demand.

There is no change in the Test processing flows. Load boards are the same at the qualified facilities. IDT has completed the electrical test correlation and based on the test results we do not anticipate any impact on device performance. The testing is fully compatible and transferrable between the test facilities with no change to the test coverage.

If you require samples to conduct evaluations, please contact your local sales representative to acknowledge this PCN and request samples.



## PRODUCT/PROCESS CHANGE NOTICE (PCN)

#### ATTACHMENT I - PCN #: TB1904-01

# **Qualification Information and Qualification Data: Electrical Test Correlation Results (IDT versus KYEC)**

Vehicle: P9242-G2NDGI

Sample size: 20 good and 5 reject units; 33 loop test correlation

Description	Existing Test (IDT, Penang)	Alternate Test (KYEC, Taiwan)
Tester Platform	iFLEX	iFLEX
Test Program	P9242-G2_R01	P9242-G2_R01
Test Site	Quad Site	Quad Site
Test Temperature	Ambient	Ambient
Test Correlation Results	100%	100%
Number of Good Units	20 pcs	20 pcs
20 good units datalog correlation	Passed	Passed
Number of Loop Test	33	33
4 good unit datalog correlation	Passed	Passed
Number of Reject Units	5 pcs	5 pcs
5 reject units datalog correlation	Passed	Passed

#### **Electrical Test Correlation Results (IDT versus ASEK)**

Vehicle: P9242-G2NDGI

Sample size: 20 good and 5 reject units; 33 loop test correlation

Description	Existing Test (IDT, Penang)	Alternate Test (ASEK, Taiwan)
Tester Platform	iFLEX	iFLEX
Test Program	P9242-G2_R01	P9242-G2_R01
Test Site	Quad Site	Quad Site
Test Temperature	Ambient	Ambient
Test Correlation Results	100%	100%
Number of Good Units	20 pcs	20 pcs
20 good units datalog correlation	Passed	Passed
Number of Loop Test	33	33
4 good unit datalog correlation	Passed	Passed
Number of Reject Units	5 pcs	5 pcs
5 reject units datalog correlation	Passed	Passed